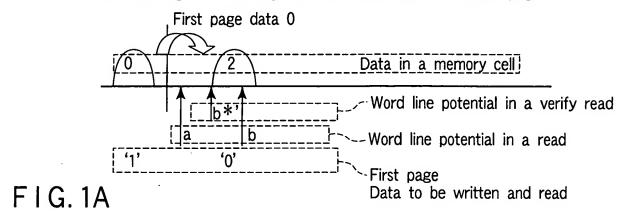
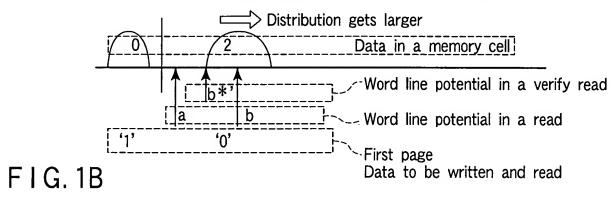
Hogan & Hartson 81790.0309 Noboru SHIBATA et al. Semiconductor Memory Device... EV 324 111 928 US 52 Drawing Sheets; Sheet 1 of 52

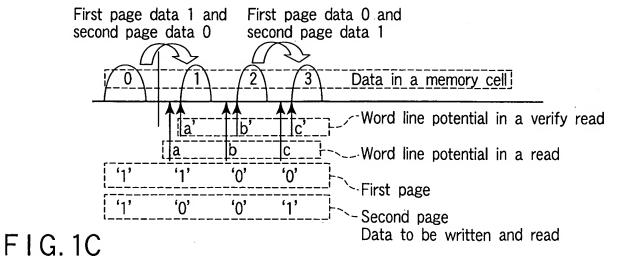
After writing the first page and before writing the second page



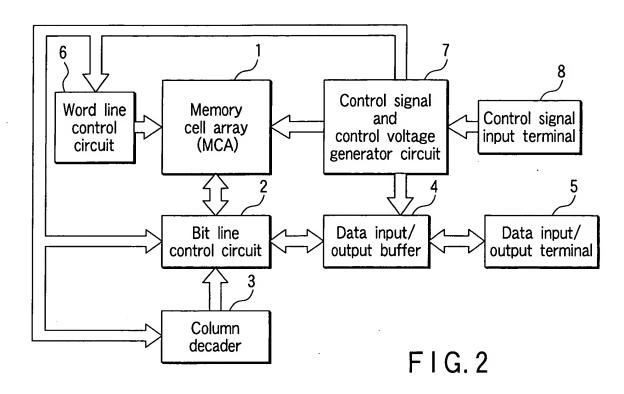
Before writing the second page and after writing the adjacent cells

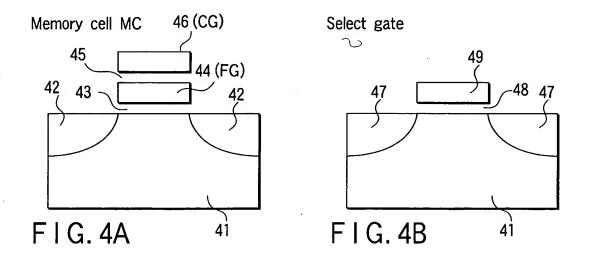


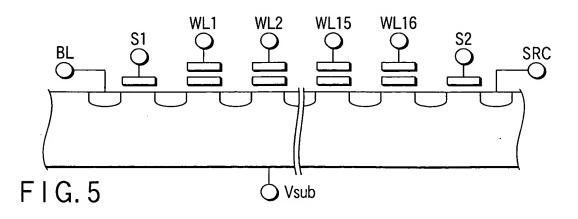
After writing the second page



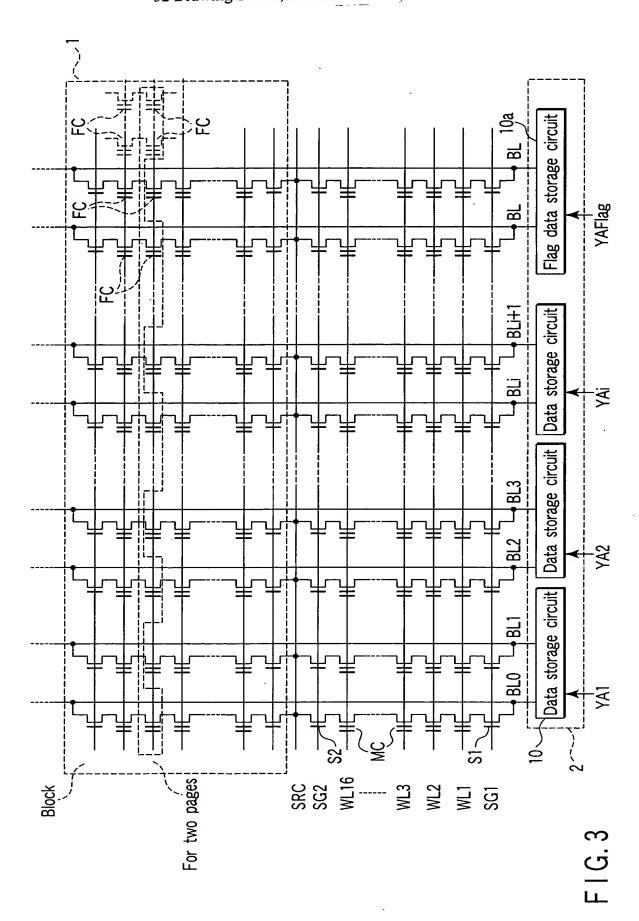
Hogan & Hartson 81790.0309 Noboru SHIBATA et al. Semiconductor Memory Device... EV 324 111 928 US 52 Drawing Sheets; Sheet 2 of 52



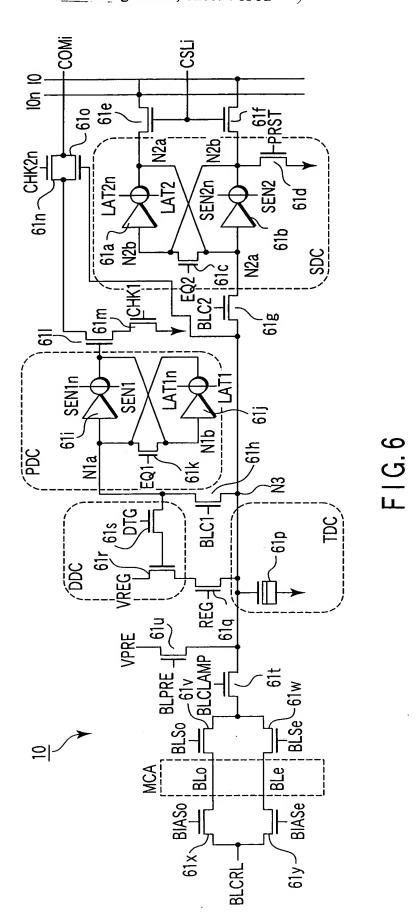




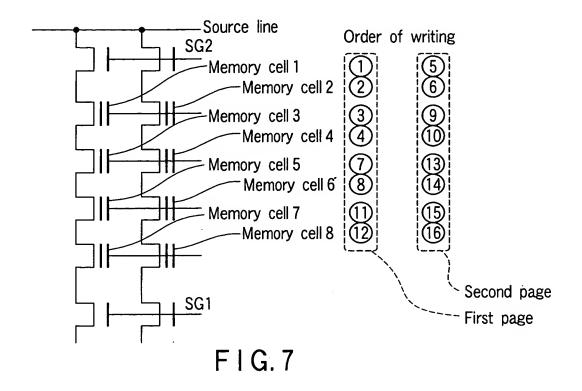
Hogan & Hartson 81790.0309 Noboru SHIBATA et al. Semiconductor Memory Device... EV 324 111 928 US 52 Drawing Sheets; Sheet 3 of 52

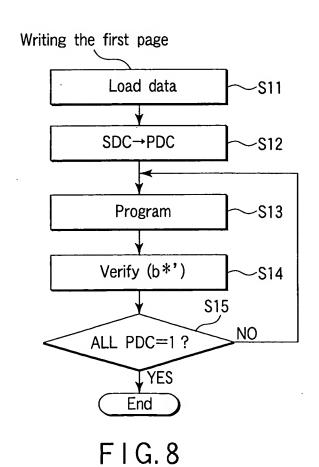


Hogan & Hartson 81790.0309 Noboru SHIBATA et al. Semiconductor Memory Device... EV 324 111 928 US 52 Drawing Sheets; Sheet 4 of 52



Hogan & Hartson 81790.0309 Noboru SHIBATA et al. Semiconductor Memory Device... EV 324 111 928 US 52 Drawing Sheets; Sheet 5 of 52





Hogan & Hartson 81790.0309 Noboru SHIBATA et al. Semiconductor Memory Device... EV 324 111 928 US 52 Drawing Sheets; Sheet 6 of 52

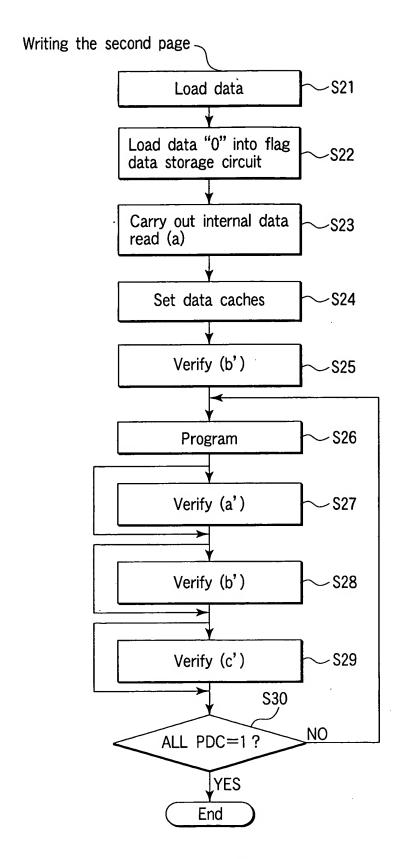


FIG. 9

Hogan & Hartson 81790.0309 Noboru SHIBATA et al. Semiconductor Memory Device... EV 324 111 928 US 52 Drawing Sheets; Sheet 7 of 52

After data load and internal read	load and I	nternal re	ad		
	Data in	memory	Data in memory cell after writing	writing	
	0	-	2	က	
SDC	-	0	0	-	Data to be written and read inputted from the outside world
PDC	0	0	1		Data read by internal read

After setting data caches

	Data in	Data in memory cell after writing	cell after	writing	
	0	-	2	က	
SDC	-	-	0	0	Used for charging in verifying memory cell data 1
DDC	0	-		0	Used for charging in verifying memory cell data 2
PDC	-	0	0	0	1 : Write unselected 0 : Write

F | G. 11

	Data in memory cell after writing	After internal data read	Copy data in PDC into DDC	Copy data in SDC into PDC	TDC=H	VREG=L, REG=H	Copy data in TDC into SDC	Copy data in PDC into TDC	VREG=L, REG=H	Copy data in PDC into DDC	Copy data in TDC into PDC
	3					(0	0		(0	(0	0
TDC	2				-	0	0	0	0	0	0
]]	-						-	0	0	0	0
	0									(-)	
	3		-		.0	7		·		1	0
PDC	2	-		0	0	0	0	0	0	0	0
<u>a</u>	-	0	0	0	0	0	0	0	0	0	0
	0	0	0		-/	-		-		-	
	3			<u>*</u>		-	-		- ,	(-)	-
DDC	2		1	/-	-	-	\ -	-	-	0	0
۵	-		0	0	0	0	0	0	0	0	0
	0		0	0	(0)	0	0	(0)	0		-
	က			-	-	-	0	0	0	0	0
SDC	2	0	0	0	0	0	0	0	0	0	0
S	-	0	0	0	0	0	1	-	-	-	-
	0	-		-	-	-		←.	-	-	

Hogan & Hartson 81790.0309 Noboru SHIBATA et al.

Semiconductor Memory Device... EV 324 111 928 US 52 Drawing Sheets; Sheet 8 of 52

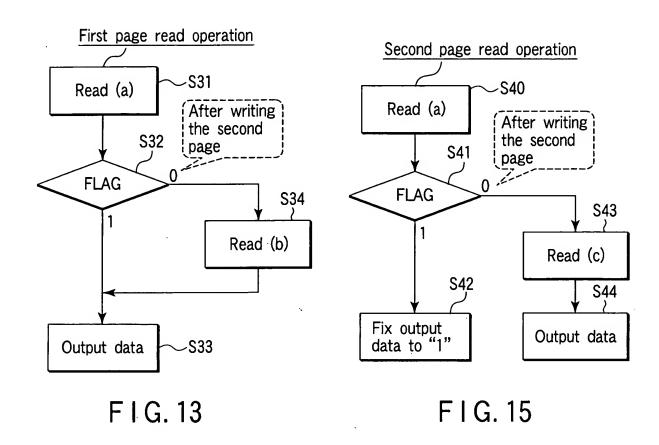
Data cache setting procedure

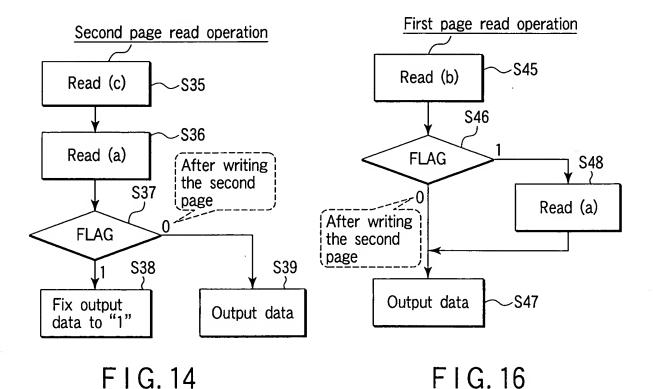
Hogan & Hartson 81790.0309 Noboru SHIBATA et al. Semiconductor Memory Device... EV 324 111 928 US 52 Drawing Sheets; Sheet 9 of 52

		,						
TDC=H	VREG=L, REG=H	Copy data in PDC into DDC	Copy data in TDC into PDC	TDC=L	VREG=H, REG=H	Copy data in PDC into DDC	Copy data in TDC into PDC	
	(0	0	0	0)	(0	(0	0	
1	-	-	•	0	0	0	0	TPC
1	1	1	l	0	0	0	0	Ŧ
	0)	0)	0	0			-	
0	10	0	(0	0	0	0	0	
0	0	0	1	-	_	-	0	PDC
0	0	0	1	-	1	l	0	П
-/		ļ	0)	0	0)	0		
	-	(0)	0	0)	0	(0)	0	
0	0	0	0	0	0	1	l	DDC
0	0	0	0	0	0	1	-	2
			-		-	0)	0	
0	0	0	0	0	0	0	0	
0	0	0	0	0	0	0	0	SDC
1	-	-		1	-		-	SE
-	_	-			-	-	-	

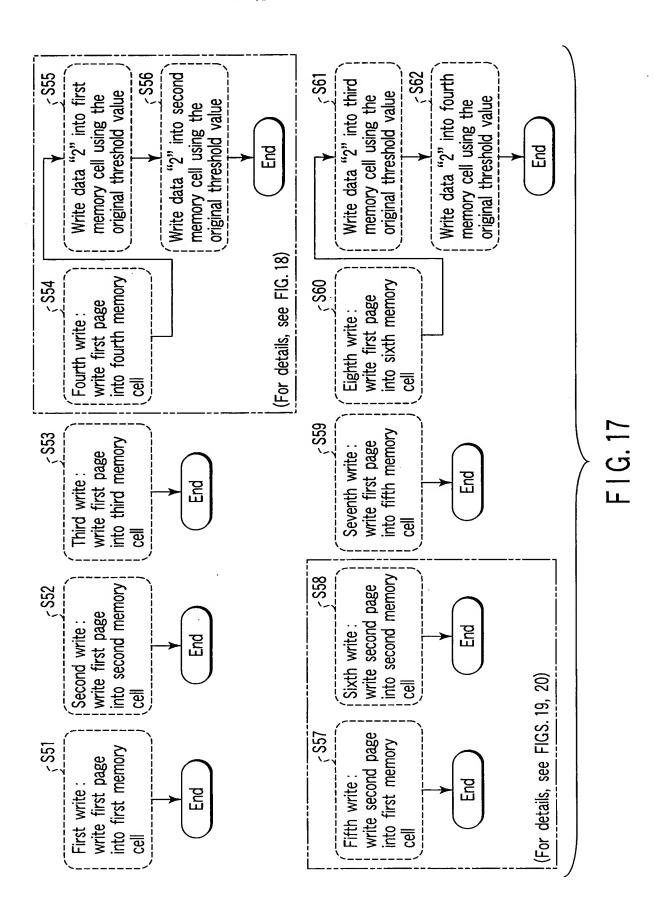
F1G. 12

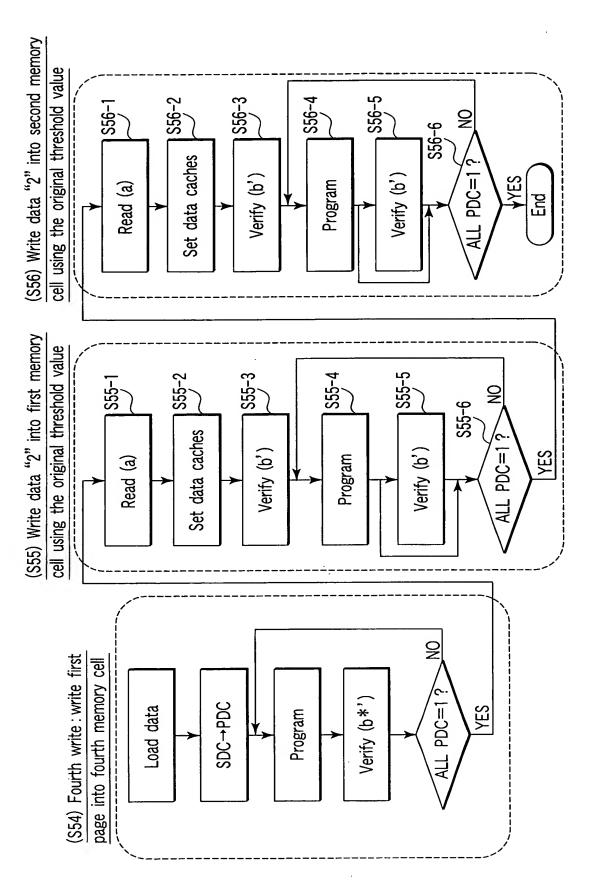
Hogan & Hartson 81790.0309 Noboru SHIBATA et al. Semiconductor Memory Device... EV 324 111 928 US 52 Drawing Sheets; Sheet 10 of 52





Hogan & Hartson 81790.0309 Noboru SHIBATA et al. Semiconductor Memory Device... EV 324 111 928 US 52 Drawing Sheets; Sheet 11 of 52





F1G. 18

Hogan & Hartson 81790.0309 Noboru SHIBATA et al. Semiconductor Memory Device... EV 324 111 928 US 52 Drawing Sheets; Sheet 13 of 52

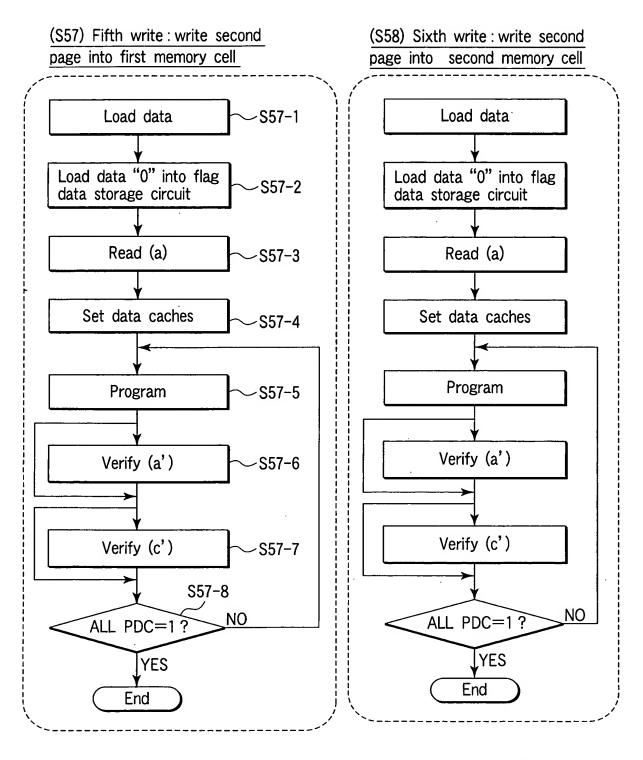
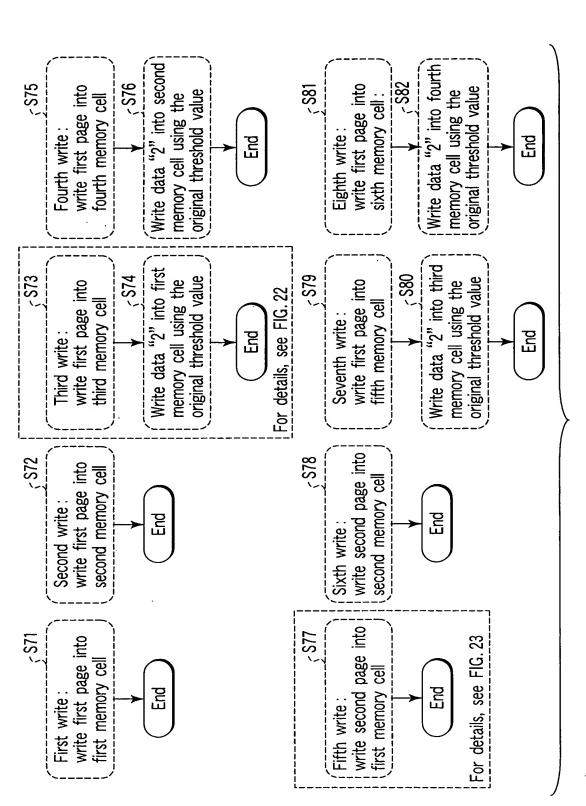


FIG. 19

FIG. 20

Hogan & Hartson 81790.0309 Noboru SHIBATA et al. Semiconductor Memory Device... EV 324 111 928 US 52 Drawing Sheets; Sheet 14 of 52



F1G.21

Hogan & Hartson 81790.0309 Noboru SHIBATA et al. Semiconductor Memory Device... EV 324 111 928 US 52 Drawing Sheets; Sheet 15 of 52

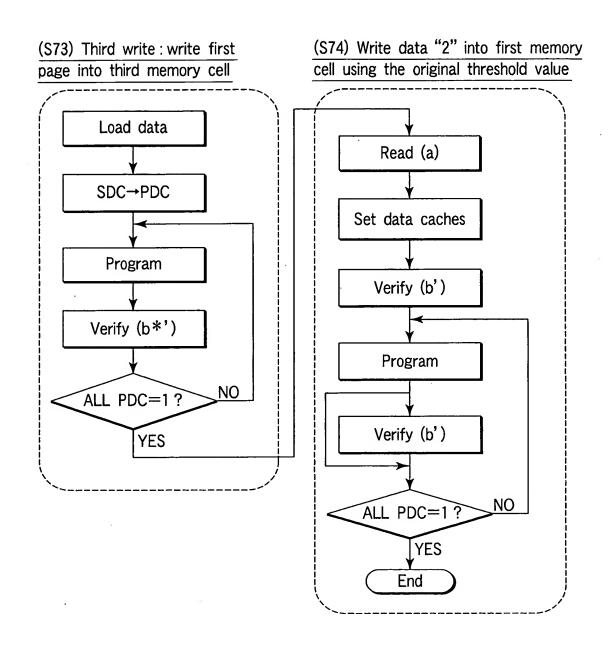
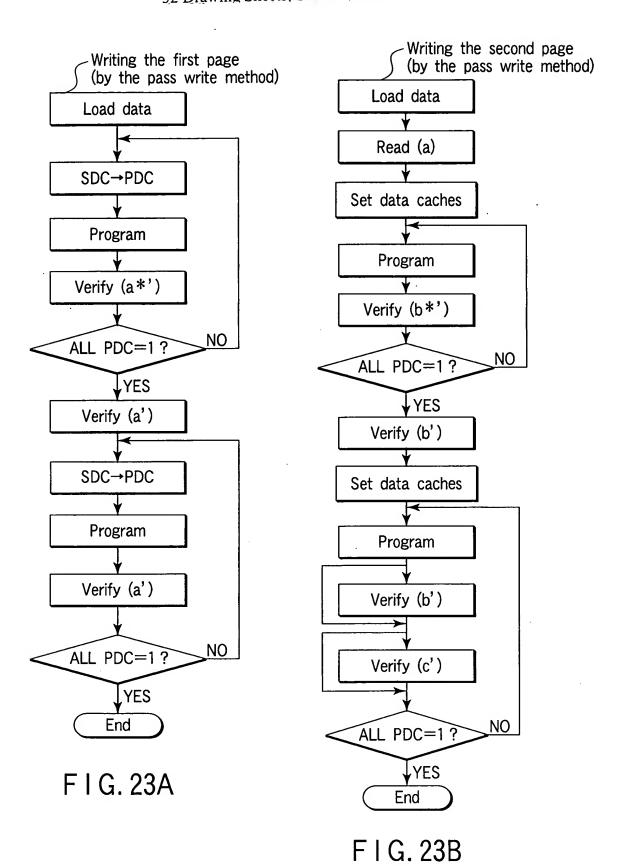


FIG. 22

Hogan & Hartson 81790.0309 Noboru SHIBATA et al. Semiconductor Memory Device... EV 324 111 928 US 52 Drawing Sheets; Sheet 16 of 52



Hogan & Hartson 81790.0309 Noboru SHIBATA et al. Semiconductor Memory Device... EV 324 111 928 US 52 Drawing Sheets; Sheet 17 of 52

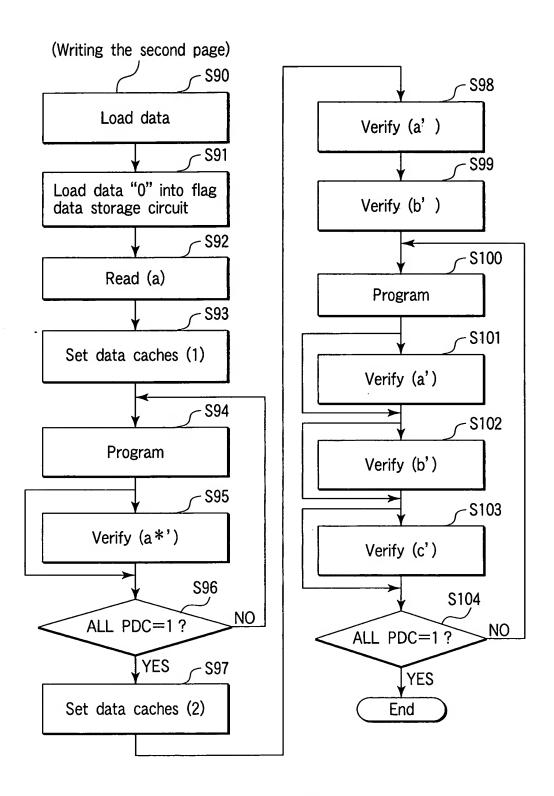


FIG. 24

Hogan & Hartson 81790.0309 Noboru SHIBATA et al. Semiconductor Memory Device... EV 324 111 928 US 52 Drawing Sheets; Sheet 18 of 52

1: Write unselected 0: Write Data in memory cell after writing က ~ 0 0 0 Data cache setting 1 0 0 200 PDC SDC

F1G. 25

Hogan & Hartson 81790.0309 Noboru SHIBATA et al. Semiconductor Memory Device... EV 324 111 928 US 52_Drawing Sheets; Sheet 19 of 52

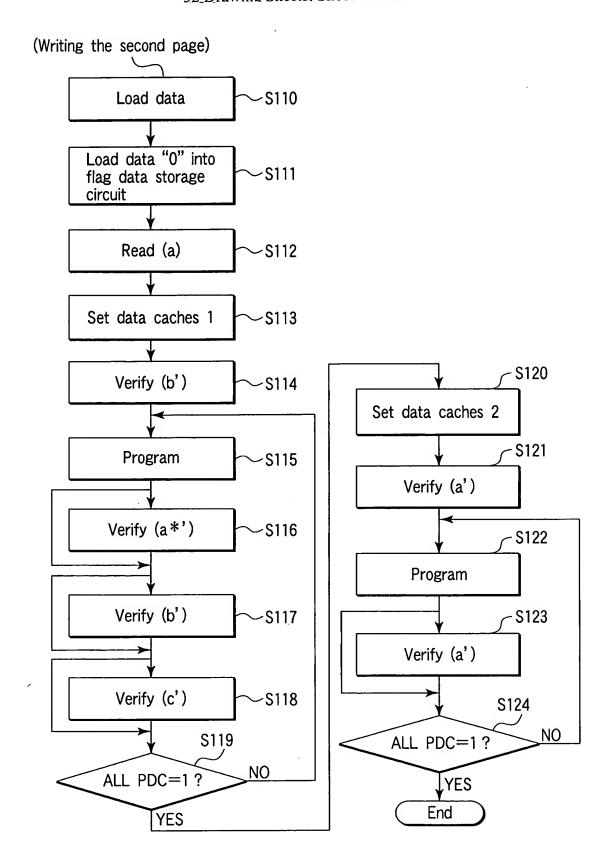


FIG. 26

Hogan & Hartson 81790.0309 Noboru SHIBATA et al. Semiconductor Memory Device... EV 324 111 928 US 52 Drawing Sheets; Sheet 20 of 52

~

Used far charging in verifying memory cell data Used for charging in verifying memory cell data 1: Write unselected 0: Write Data in memory cell after writing 0 က 0 0 2 0 0 0 Data cache setting 1 0 0 200 SDC F1G.27A

			1 : Write unselected 0 : Write
Tr.	. writing	. 8	-
	ta in memory cell after writing	2	l
	memory	-	0
setting 2	Data in	0	-
Data cache settir			PDC

1G. 27B

Hogan & Hartson 81790.0309 Noboru SHIBATA et al. Semiconductor Memory Device... EV 324 111 928 US 52 Drawing Sheets; Sheet 21 of 52

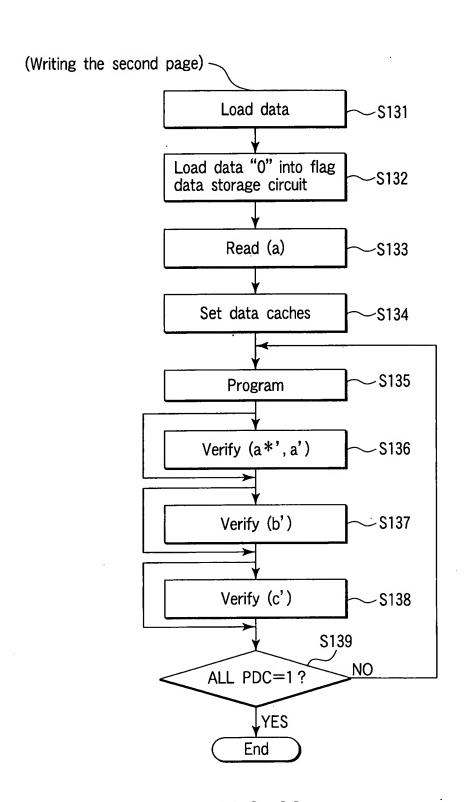


FIG. 28

Hogan & Hartson 81790.0309 Noboru SHIBATA et al. Semiconductor Memory Device... EV 324 111 928 US 52 Drawing Sheets: Sheet 22 of 52

After data load and internal read

יווכן ממומ וווכווומן וכמת	ממ מוס	3 3	3		
	Data in	Data in memory cell after writing	cell after	writing	
	0	-	2	က	
SDC	-	0	0	-	Data to be written and read inputted from the outside world
PDC	0	0	-		Data read by internal read

After data cache setting

	Data in	memory	memory cell after writing	r writing	
	0	-	2	က	
SDC	0	-	-	0	0 Used for charging in verifying memory cell data 2
DDC	-	0	-	-	Used for precharging bit line in programming and for charging in verifying memory cell data 1
PDC	-	1/0	0	0	0 1: Write unselected 0: Write

1 G. 29B

Hogan & Hartson 81790.0309 Noboru SHIBATA et al. Semiconductor Memory Device... EV 324 111 928 US 52 Drawing Sheets; Sheet 23 of 52

	Prechar	Precharge bit line on the		basis of the data in DDC	e data in	DDC
		Data ir	Data in memory cell after writing	cell after	writing	
		0	-	2	3	
F1G.30A	Bit line	ρρΛ	F (Vss)	Vdd	Vdd	
	With BL	-C1 = Vcl	With BLC1 = Vclamp, connect PDC to bit line	ect PDC to	o bit line	•
		Data ir	Data in memory	y cell after writing	writing	
		0	-	2	က	
F1G.30B	Bit line	γdd	0/Inter- mediate	0	0	
	During	During program recovery,		ransfer da	ta in PDC	transfer data in PDC to DCC, invent data in DDC, and transfer the inverted data to PDC
		Data ir	Data in memory cell after writing	cell after	writing	
		0	-	2	ဗ	
	SDC	0	_	•	0	Used for charging in verifying memory cell data 2
	DDC	-	1/0	0	0	1 : Write unselected 0 : Write
F1G 30C	PDC	0	-	0	0	Used for precharging bit line in programming and for charging in verifying memory cell data 1

Hogan & Hartson 81790.0309 Noboru SHIBATA et al. Semiconductor Memory Device... EV 324 111 928 US 52 Drawing Sheets; Sheet 24 of 52

Verify (a) Charge bit line on the basis of data in PDC Discharge bit line at a potential of WL = a* Invert data in PDC while discharging bit line

	Data in		memory cell after writing	writing	
	0	-	2	က	
SDC	0	-	_	0	Used for charging in verifying memory cell data 2
DDC	1	1/0	0	0	0 1: Write unselected 0: Write
PDC	-	0	,	-	Used far precharging bit line in programming and for charging in verifying memory cell data 1

Load the potential of bit line into TDC With VREG = H and REG = H, make TDC 1 when dynamic data is 1 Transfer data in PDC ta DDC and data in TDC to PDC

	Data in		memory cell after writing	writing	
	0	-	2	3	
SDC	0	1	ļ	0	0 Used far charging in verifying memory cell data 2
DDC	1	0	0	-	User for precharging bit line in programming and for chagrining in verifying memory cell data 1
PDC	Ţ	0/1	ļ	1	1 : Write unselected 0 : Write

-1G.31B

Hogan & Hartson 81790.0309 Noboru SHIBATA et al. Semiconductor Memory Device... EV 324 111 928 US 52_Drawing Sheets: Sheet 25 of 52

With WL = a', discharge bit line With VREG = H and REG = H, set 1 in TDC when dynamic data is 1 Transfer data in PDC to DDC Transfer data in TDC to PDC

Data in memory cell after writing

	0	-	2	က	
SDC	0	_		0	0 Used for charging in verifying memory cell data 2
DDC	1	0/1	0	0	0 1: Write unselected 0: Write
PDC	-	0	-	1	Used for precharging bit line in programming and for charging in verifying memory cell data 1
Transfer	ransfer data in DDC to PDC	DDC to F	C to PDC		

Then, transfer data in PDC to DDC

	Data in mer	memory	nory cell after writing	writing	
	0	_	2	3	
SDC	0	-	-	0	Used for charging in verifying memory cell data 2
DDC		0	-	-	Used for precharging bit line in programming and for charging in verifying memory cell data 1
PDC	-	1/0	0	0	1 : Write unselected 0 : Write

Hogan & Hartson 81790.0309 Noboru SHIBATA et al. Semiconductor Memory Device... EV 324 111 928 US 52 Drawing Sheets; Sheet 26 of 52

With memory cell data 1, all of the writing with verify (a^*) is completed (the writing with verify (a^*) might nat be completed)

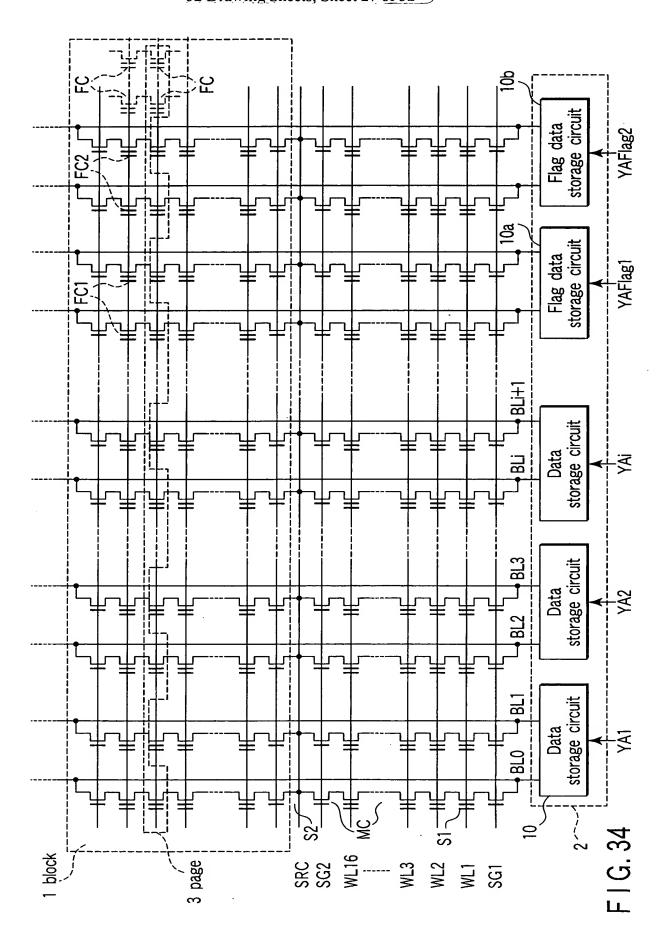
	Data in men	memory	nory cell after writing	writing .	
	0		2	က	
SDC	0	-		0	Used far charging in verifying memory cell data 2
DDC	1	0	-	1	Used for precharging bit line in programming and for charging in verifying memory cell data 1
PDC	-	-	0	0	1 : Write unselected 0 : Write

With memory cell data 1, all of the writing with verify (a') is completed (the writing with verify (a') might not be completed)

	Data in mem		ory cell after writing	writing	
	0		2	က	
SDC	0	-		0	Used for charging in verifying memory cell data 2
DDC	-	-	_	-	Used for precharging bit line in programming and for charging in verifying memory cell data 1
PDC	-		0	0	1 : Write unselected 0 : Write

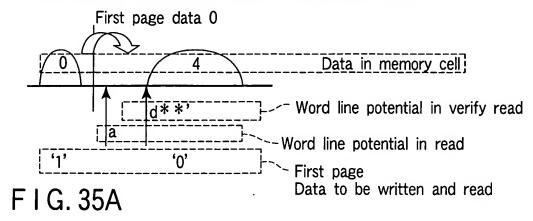
1 G. 33B

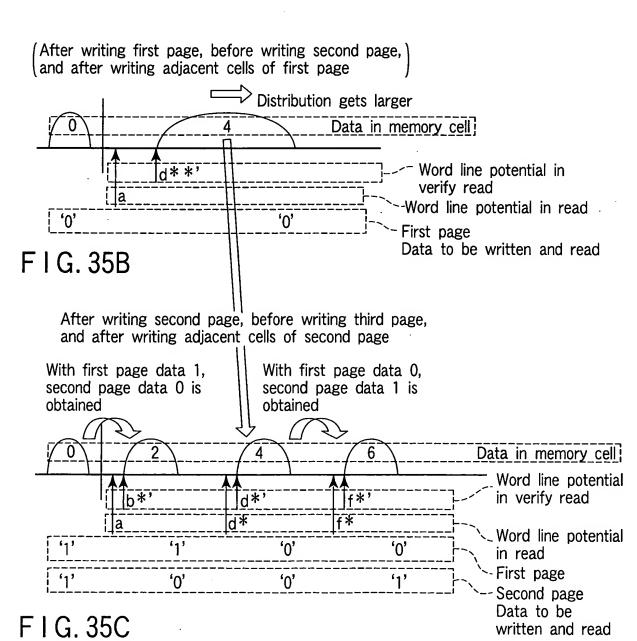
Hogan & Hartson 81790.0309 Noboru SHIBATA et al. Semiconductor Memory Device... EV 324 111 928 US 52 Drawing Sheets; Sheet 27 of 52



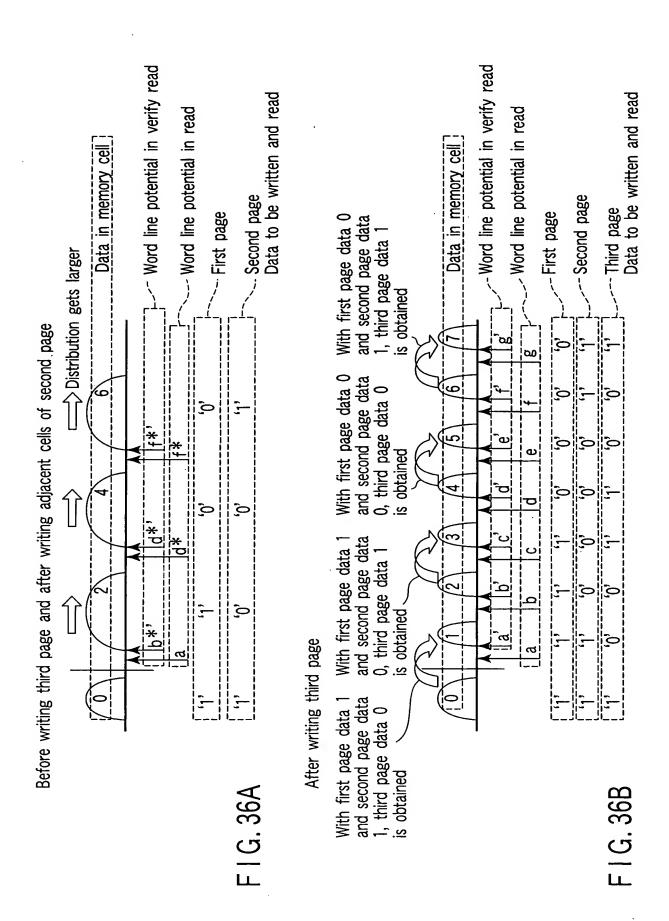
Hogan & Hartson 81790.0309 Noboru SHIBATA et al. Semiconductor Memory Device... EV 324 111 928 US 52 Drawing Sheets: Sheet 28 of 52

(After writing first page and before writing second page)

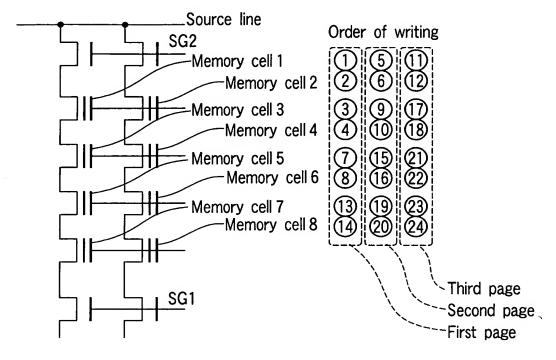




Hogan & Hartson 81790.0309 Noboru SHIBATA et al. Semiconductor Memory Device... EV 324 111 928 US 52 Drawing Sheets; Sheet 29 of 52



Hogan & Hartson 81790.0309 Noboru SHIBATA et al. Semiconductor Memory Device... EV 324 111 928 US 52 Drawing Sheets; Sheet 30 of 52



F I G. 37A

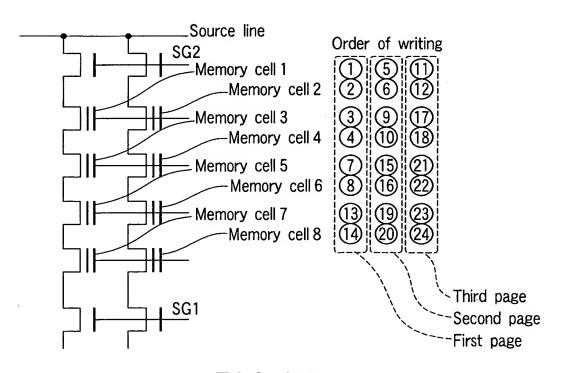
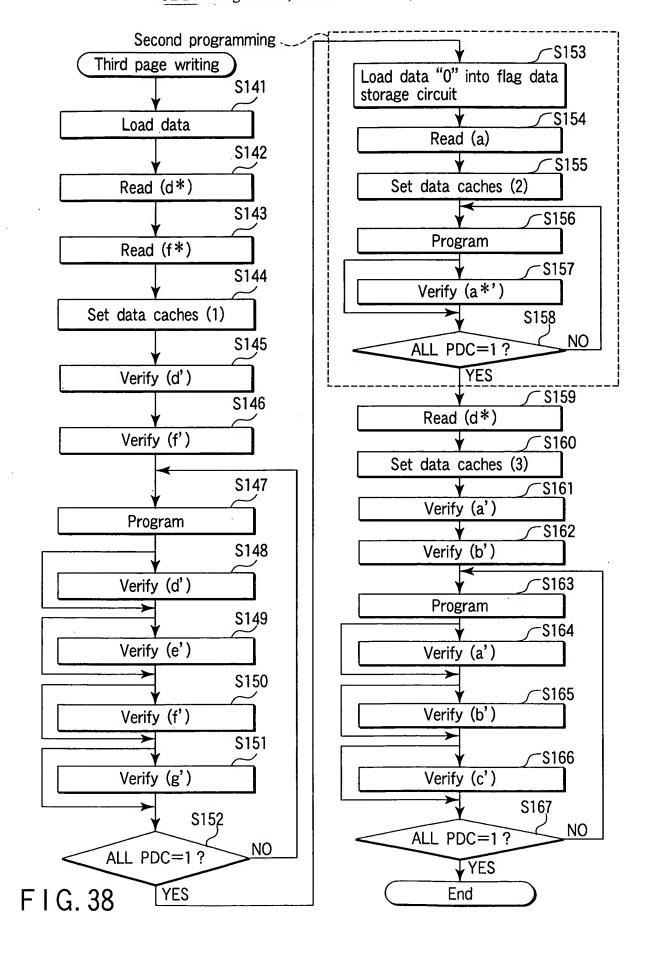


FIG. 37B

Hogan & Hartson 81790.0309 Noboru SHIBATA et al. Semiconductor Memory Device... EV 324 111 928 US 52 Drawing Sheets; Sheet 31 of 52



Hogan & Hartson 81790.0309 Noboru SHIBATA et al. Semiconductor Memory Device... EV 324 111 928 US 52 Drawing Sheets; Sheet 32 of 52

After third page data load internal read 1

		Data in	n mei	mory	memory cell after writing	ıfter	writin	20	
	0	-	2	3	3 4 5 6	5	9	7	
SDC	-	0	0	-	-	0	0	-	1 0 0 1 Data to be written and read inputted from the outside world
DDC	0	0	0	0	0 0 0 1	0		-	1 Data to be read by internal read
PDC	0	0	0	0	1	-	-	-	Data to be read by internal read

After third page data cache setting 1

	ט	ata i	n me	mory	cell ;	Data in memory cell after writing	writin	ත	
	0	·	2	က	4	3 4 5 6 7	9	7	
SDC	-	-	-	-	-		0	0	1 1 0 0 Used far charging in verifying memory cell data items 5, 4
DDC	0	-	-	0	0 0	-	-	0	Used for charging in verifying memory cell data 6 Forced to be at VSS in verifying memory cell data 4
PDC	-	_	_	-	0	0	0	0	1 0 0 0 1: Write unselected 0: Write

FIG. 39B

Hogan & Hartson 81790.0309 Noboru SHIBATA et al. Semiconductor Memory Device... EV 324 111 928 US 52 Drawing Sheets; Sheet 33 of 52

After third page data cache setting 2

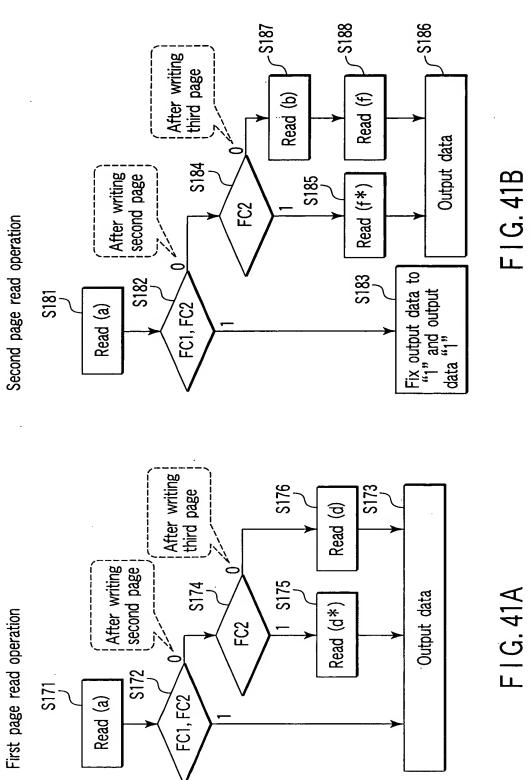
	ا	Data in		mory	s lles	memory cell after writing	writin	500	
	0	-	2	33	4	2	9	7	
SDC		-	0	0	0	0 0 0	0	0	
DDC	0	-	-	0	0	-	-	0	
PDC	-	0	-	-	-	-	-	-	1 : Write unselected 0 : Write

After third page data cache setting 3

	ப	ata i	n me	mory	cell s	Data in memory cell after writing	writin	ρ.0	
	0		2	က	4	3 4 5 6 7	9	7	
SDC	-	-	0	0	0	0	0.	0	0 0 0 0 Used for charging in verifying memory cell data 1
DDC	0	_	-	0	0	-	-	0	0 0 1 1 0 Used for charging in verifying memory cell data 2
PDC	-	0	0	0 1	-	-	-	-	1 : Write unselected 0 : Write

FIG. 40B

Hogan & Hartson 81790.0309 Noboru SHIBATA et al. Semiconductor Memory Device... EV 324 111 928 US 52 Drawing Sheets; Sheet 34 of 52



Hogan & Hartson 81790.0309 Noboru SHIBATA et al. Semiconductor Memory Device... EV 324 111 928 US 52 Drawing Sheets; Sheet 35 of 52

Third page read operation

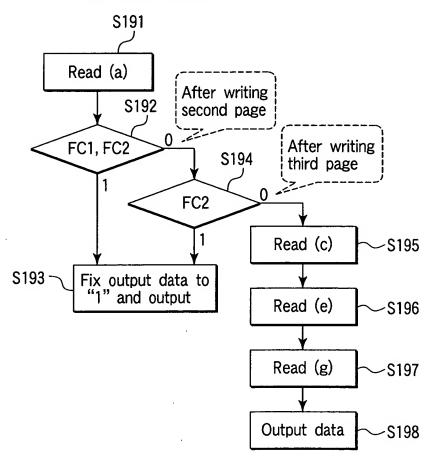


FIG. 42

Hogan & Hartson 81790.0309 Noboru SHIBATA et al. Semiconductor Memory Device... EV 324 111 928 US 52 Drawing Sheets; Sheet 36 of 52

After data load and internal read

	Data in		nemory cell after writing	writing	
	0	1	2	3	
SDC	-	0	0	-	Data to be written and read inputted from the outside world
PDC	0	0		-	Data read by internal read

F | G. 43A

After setting data caches

	Data in		nemory cell after writing	writing	
	0		2	3	
SDC	ı	-	0	0	Used for charging in verifying memory cell data 1
DDC	0	0		0	Used for charging in verifying memory cell data 2
PDC	1	0	0	0	1 : Write unselected, 0 : Write

F I G. 43B

Hogan & Hartson 81790.0309 Noboru SHIBATA et al. Semiconductor Memory Device... EV 324 111 928 US 52 Drawing Sheets; Sheet 37 of 52

Verify (a*')Charge bit line on the basis of data in SDC Discharge bit line at a potential of WL=a*'

	Data in	memory	Data in memory cell after writing	writing	
	0	-	2	3	
SDC		-	0	0	Used for charging in verifying memory cell data 1
DDC	0	0		0	Used for charging in verifying memory cell data 2
PDC	1	0	0	0	1 : Write unselected, 0 : Write

Set Vdd in TDC and transfer the potential of bit line to TDC when BLCLAMP is H With VREG=H, REG=H, make TDC 1 when dynamic data is 1 Transfer data in PDC to DDC and data in TDC to DDC

	Data in	memory	Data in memory cell after writing	writing	
	0		2	3	
SDC	1	ļ	0	0	Used for charging in verifying memory cell data 1
DDC	l	0	0	0	0 1 : Write unselected, 0 : Write
PDC	0	1/0	-	0	Used for charging in verifying memory cell data 2 When threshold voltage in memory cell into which data 1 is written exceeds $a^* \rightarrow 1$

F I G. 44B

Hogan & Hartson 81790.0309 Noboru SHIBATA et al. Semiconductor Memory Device... EV 324 111 928 US 52 Drawing Sheets; Sheet 38 of 52

Discharge bit line at a potential of WL=a' Set Vdd in TDC and transfer the potential of bit line to TDC when BLCLAMP is H With VREG=H, REG=H, make TDC 1 when dynamic data is 1 Transfer data in PDC to DDC and data in TDC to DDC

	Da	Data in memory cell after writing	nory cell	after writi	ng	
	0	1pass	1 pass 1 fail 2	2	3	
SDC	1	1	-	0	0	Used for charging in verifying memory cell data 1
DDC	0	-	0/1	-	0	Used for charging in verifying memory cell data 2 When threshold voltage in memory cell into which data 1 is written exceeds a^* , \rightarrow 1
PDC	1	-	0	0	0	0 1: Write unselected, 0: Write

F I G. 45A

Hogan & Hartson 81790.0309 Noboru SHIBATA et al. Semiconductor Memory Device... EV 324 111 928 US 52 Drawing Sheets; Sheet 39 of 52

Discharge bit line at a potential of WL=b' Transfer data in DDC to TDC, PDC to DDC and TDC to PDC during the discharge Set Vdd in TDC and transfer the potential of bit line to TDC when BLCLAMP is H With VREG=H, REG=H, make TDC 1 when dynamic data is 1 Transfer data in PDC to DDC and data in TDC to DDC Charge bit line on the basis of data in DDC

	Da	ita in mer	nory cell	Data in memory cell after writing	JB BL	
	0	l	2fail 2pass	2pass	3	
SDC	1	1.	0	0	0	Used for charging in verifying memory cell data 1
DDC	0	0/1	l		0	Used for charging in verifying memory cell data 2 When threshold voltage in memory cell into which data 1 is written exceeds $a^* \rightarrow 1$
PDC	1	0	0		0	0 1: Write unselected, 0: Write

FIG. 45B

Hogan & Hartson 81790.0309 Noboru SHIBATA et al. Semiconductor Memory Device... EV 324 111 928 US 52 Drawing Sheets; Sheet 40 of 52

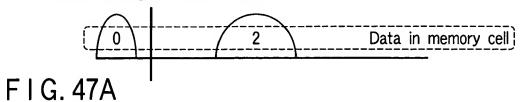
Transfer data in DDC to TDC, PDC to DDC and TDC to PDC during the discharge Set Vdd in TDC and transfer the potential of bit line to TDC when BLCLAMP is H With VREG=H, REG=H, make TDC 1 when dynamic data is 1 Transfer data in PDC to DDC and data in TDC to DDC Discharge bit line at a potential of WL=c' Charge bit line

	Da	Data in memory cell after writing	nory cell	after writi	ng	
	0	1	2	3fail 3pass	3pass	
SDC	-	1	0	0	0	Used for charging in verifying memory cell data 1
DDC	0	1/0	-	0	0	Used for charging in verifying memory cell data 2 When threshold voltage in memory cell into which data 1 is written exceeds a^* \rightarrow 1
PDC	1	0	0	0	1	1 : Write unselected, 0 : Write

F1G 46

Hogan & Hartson 81790.0309 Noboru SHIBATA et al. Semiconductor Memory Device... EV 324 111 928 US 52 Drawing Sheets; Sheet 41 of 52

Before writing the second page



After writing the second page

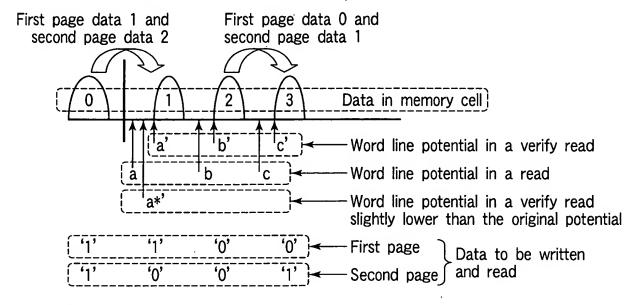
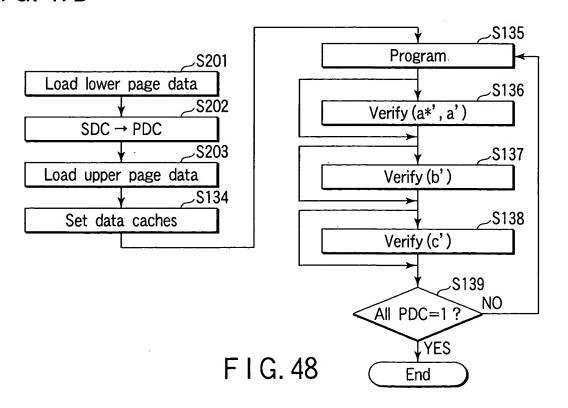


FIG. 47B



Hogan & Hartson 81790.0309 Noboru SHIBATA et al. Semiconductor Memory Device... EV 324 111 928 US 52 Drawing Sheets; Sheet 42 of 52

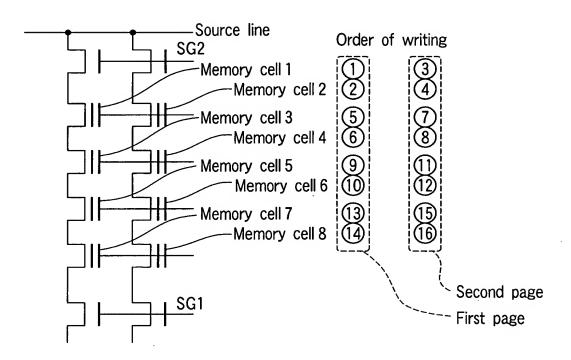
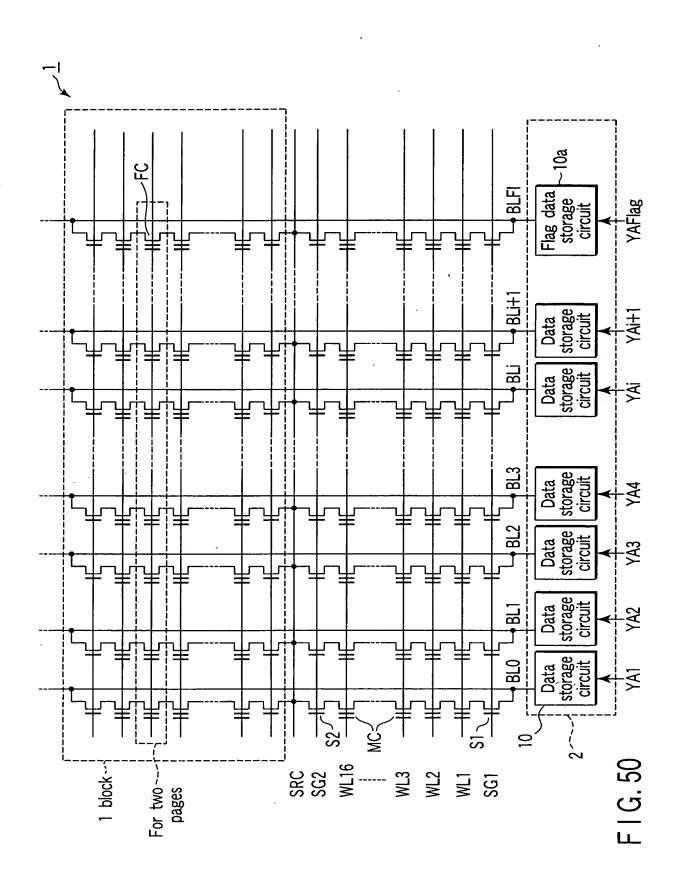
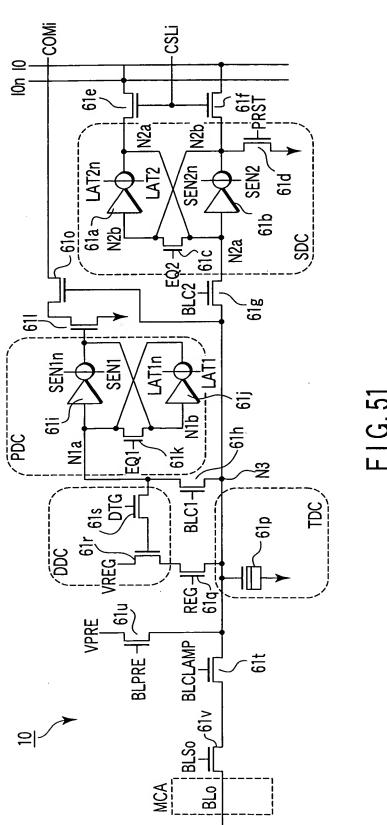


FIG. 49

Hogan & Hartson 81790.0309 Noboru SHIBATA et al. Semiconductor Memory Device... EV 324 111 928 US 52 Drawing Sheets; Sheet 43 of 52



Hogan & Hartson 81790.0309 Noboru SHIBATA et al. Semiconductor Memory Device... EV 324 111 928 US 52 Drawing Sheets; Sheet 44 of 52



Hogan & Hartson 81790.0309 Noboru SHIBATA et al. Semiconductor Memory Device... EV 324 111 928 US 52 Drawing Sheets; Sheet 45 of 52

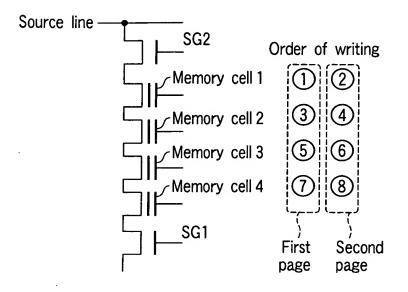


FIG. 52

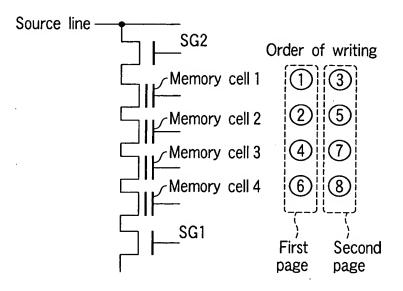
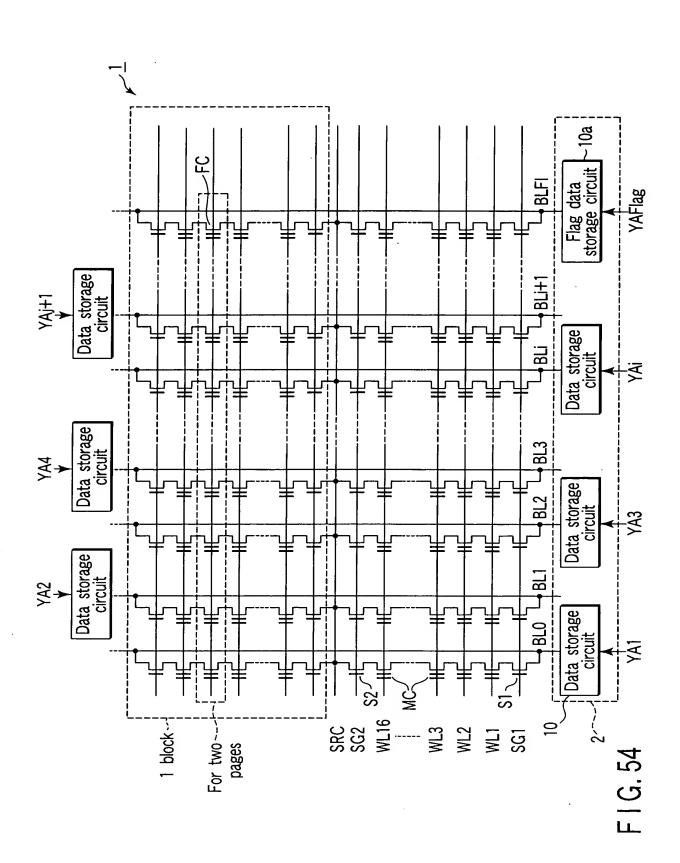
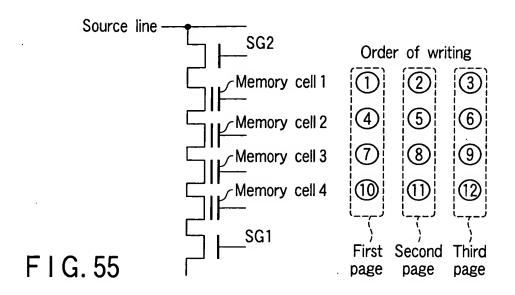


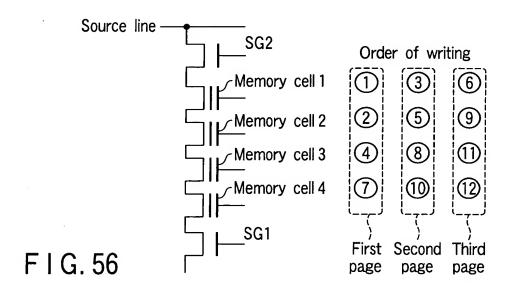
FIG. 53

Hogan & Hartson 81790.0309 Noboru SHIBATA et al. Semiconductor Memory Device... EV 324 111 928 US 52 Drawing Sheets; Sheet 46 of 52



Hogan & Hartson 81790.0309 Noboru SHIBATA et al. Semiconductor Memory Device... EV 324 111 928 US 52 Drawing Sheets; Sheet 47 of 52





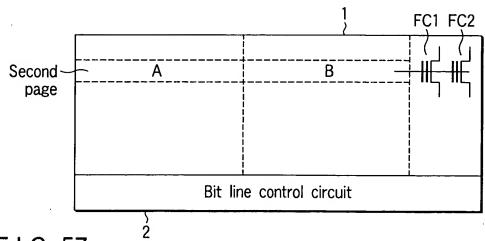
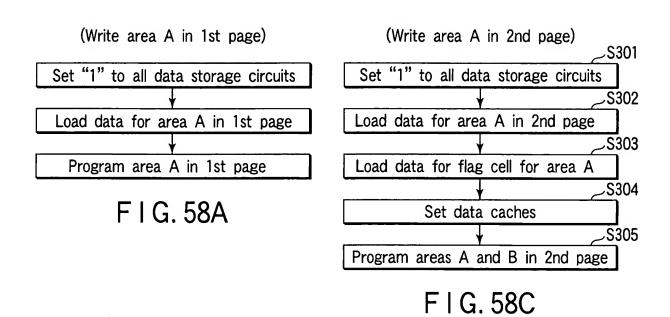


FIG. 57

Hogan & Hartson 81790.0309 Noboru SHIBATA et al. Semiconductor Memory Device... EV 324 111 928 US 52 Drawing Sheets; Sheet 48 of 52



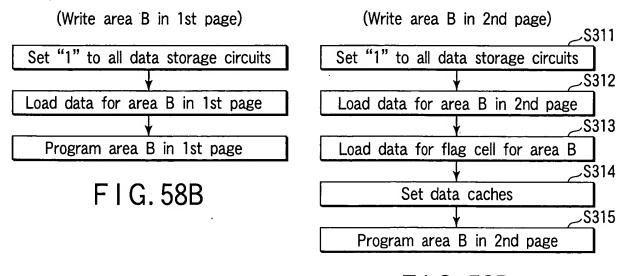
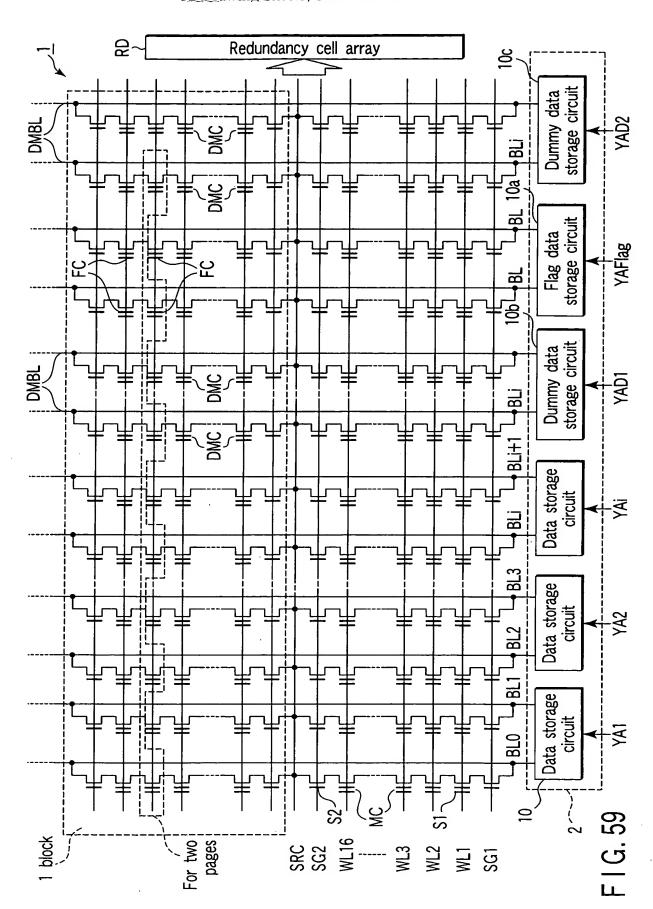


FIG. 58D

Hogan & Hartson 81790.0309 Noboru SHIBATA et al. Semiconductor Memory Device... EV 324 111 928 US 52 Drawing Sheets; Sheet 49 of 52



Hogan & Hartson 81790.0309 Noboru SHIBATA et al. Semiconductor Memory Device... EV 324 111 928 US 52 Drawing Sheets; Sheet 50 of 52

After writing the second page

Threshold distribution of a memory cell

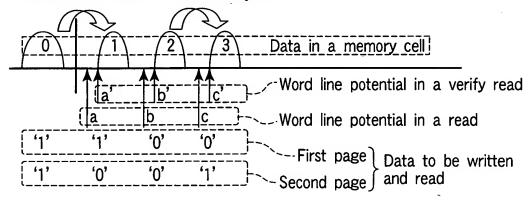


FIG. 60A

After writing the second page

Threshold distribution of a flag cell

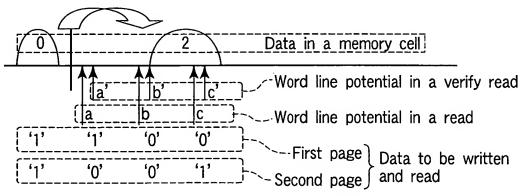


FIG. 60B

Hogan & Hartson 81790.0309
Noboru SHIBATA et al.
Semiconductor Memory Device...
EV 324 111 928 US
52 Drawing Sheets; Sheet 51 of 52

After writing the second page

Threshold distribution of the first flag cell

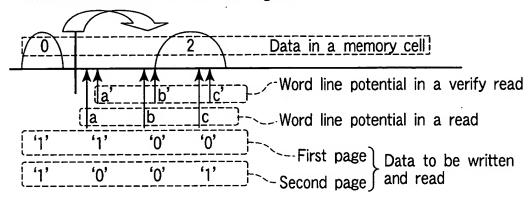


FIG. 61A

After writing the second page

Threshold distribution of the second flag cell

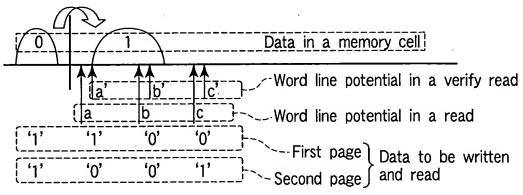
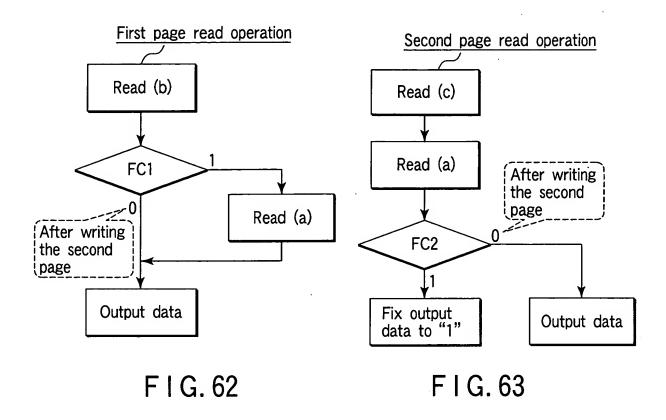


FIG. 61B

Hogan & Hartson 81790.0309 Noboru SHIBATA et al. Semiconductor Memory Device... EV 324 111 928 US 52 Drawing Sheets; Sheet 52 of 52



	BL	BL	BL	BL	BL	BL	BL	BL	BL	BL	BL	BL	BL	BL	BL	BL
	E	0	0	E	0	E	0	E	0	0	E	0	E	0	E	0
Memory cell array	Dummy cell	Second flag cell	First flag cell	Second flag cell	First flag cell	Second flag cell	First flag cell	Dummy cell	Dummy cell	First flag cell	Second flag cell	First flag cell	Second flag cell	First flag cell	Second flag cell	Dummy cell

FIG. 64